

Silicon - Diode

BA129

180V / 500mA / 500mW

High Voltage, Low Leakage Diode

DATASHEET

OEM – Fairchild

Source: Fairchild Databook 1978

BAY73 • BA129

HIGH VOLTAGE, LOW LEAKAGE DIODES

DIFFUSED SILICON PLANAR

- BV... 125 V (MIN) @ 100 μ A (BAY73)
- BV... 200 V (MIN) @ 100 μ A (BA129)

ABSOLUTE MAXIMUM RATINGS (Note 1)

Temperatures

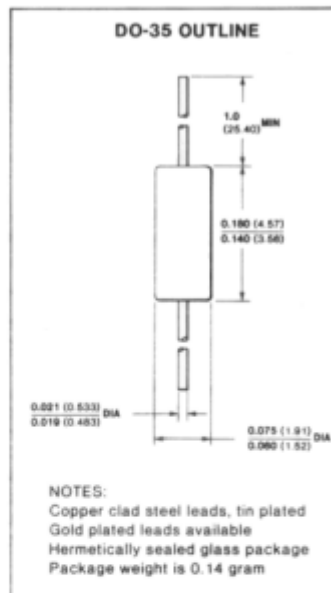
Storage Temperature Range	-65°C to +200°C
Maximum Junction Operating Temperature	+175°C
Lead Temperature	+260°C

Power Dissipation (Note 2)

Maximum Total Power Dissipation at 25°C Ambient	500 mW
Linear Power Derating Factor (from 25°C)	3.33 mW / °C

Maximum Voltage and Currents

WIV	Working Inverse Voltage	BAY73	100 V
		BA129	180 V
I_O	Average Rectified Current		200 mA
I_F	Continuous Forward Current		500 mA
i_f	Peak Repetitive Forward Current		600 mA
$i_f(\text{surge})$	Peak Forward Surge Current		1.0 A
	Pulse Width = 1 s		4.0 A
	Pulse Width = 1 μ s		



ELECTRICAL CHARACTERISTICS (25°C Ambient Temperature unless otherwise noted)

SYMBOL	CHARACTERISTIC	BAY73		BA129		UNITS	TEST CONDITIONS
		MIN	MAX	MIN	MAX		
V_F	Forward Voltage	0.85	1.00			V	$I_F = 200$ mA
		0.81	0.94			V	$I_F = 100$ mA
		0.78	0.88	0.78	1.00	V	$I_F = 50$ mA
		0.69	0.80	0.69	0.83	V	$I_F = 10$ mA
		0.67	0.75			V	$I_F = 5.0$ mA
						V	$I_F = 1.0$ mA
		0.60	0.68	0.60	0.71	V	$I_F = 0.1$ mA
I_R	Reverse Current		500			nA	$V_R = 20$ V, $T_A = 125^\circ\text{C}$
			5.0			nA	$V_R = 100$ V
			1.0			μ A	$V_R = 100$ V, $T_A = 125^\circ\text{C}$
					10	nA	$V_R = 180$ V
					5.0	μ A	$V_R = 180$ V, $T_A = 100^\circ\text{C}$
BV	Breakdown Voltage	125		200		V	$I_R = 100$ μ A
C	Capacitance		8.0		6.0	pF	$V_R = 0$, $f = 1.0$ MHz
t_{rr}	Reverse Recovery Time		3.0			μ s	$I_F = 10$ mA, $V_R = 35$ V $R_L = 1.0$ to 100 K Ω $C_L = 10$ pf, JAN 256

NOTES:

- These ratings are limiting values above which the serviceability of the diode may be impaired.
- These are steady state limits. The factory should be consulted on applications involving pulses or low duty-cycle operation.
- For product family characteristic curves, refer to Chapter 4, D2